

STD70N03L STD70N03L-1

N-channel 30V - 0.0059Ω - 70A - DPAK / IPAK STripFET™ III Power MOSFET

General features

Туре	V _{DSS}	R _{DS(on)}	۱ _D
STD70N03L	30V	<0.0073Ω	70A
STD70N03L-1	30V	<0.0073Ω	70A

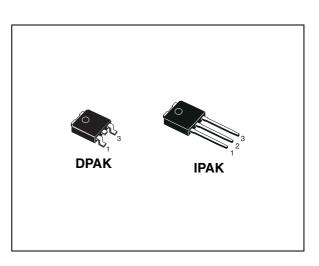
- R_{DS(ON)} * Qg industry's benchmark
- Conduction losses reduced
- Switching losses reduced
- Low threshold device

Description

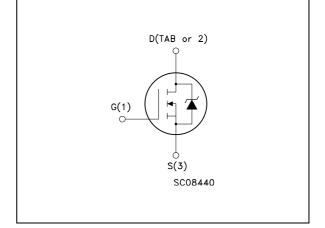
This product utilizes the latest advanced design rules of ST's proprietary STripFET[™] technology. This is suitable for the most demanding DC-DC converter application where high efficiency is to be achieved.

Applications

Switching application



Internal schematic diagram



Order codes

Part number	Marking	Package	Packaging
STD70N03L	D70N03L	DPAK	Tape & reel
STD70N03L-1	D70N03L-1	IPAK	Tube

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1 Electrical ratings

Table 1. Absolute maximum rating	as
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Symbol	Parameter	Value U		
V _{DS}	Drain-source voltage (V _{GS} = 0)	30		
V _{GS}	Gate-source voltage	± 20	V	
Ι _D	Drain current (continuous) at $T_C = 25^{\circ}C$	70		
۱ _D	Drain current (continuous) at T _C = 100°C	50		
I _{DM} ⁽¹⁾	Drain current (pulsed)	280		
P _{TOT}	Total dissipation at $T_C = 25^{\circ}C$	70		
	Derating factor	0.47 W/º		
E _{AS} ⁽²⁾	Single pulse avalanche energy	300	mJ	
T _j T _{stg}	Operating junction temperature Storage temperature	-55 to 175	°C	

1. Pulse width limited by safe operating area

2. Starting Tj = 25° C, Id = 30A, Vdd = 15V

Table 2. Thermal resistance	Table 2.	Thermal	resistance
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Symbol	Parameter	Value	Unit
Rthj-case	Thermal resistance junction-case Max	2.14	°C/W
Rthj-amb	Thermal resistance junction-amb Max	100	°C/W
Τ _Ι	Maximum lead temperature for soldering purpose	275	°C

2 Electrical characteristics

(T_{CASE}=25°C unless otherwise specified)

Symbol	Parameter	Test condictions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	I _D = 250μΑ, V _{GS} = 0	30			V
I _{DSS}	Zero gate voltage drain current ($V_{GS} = 0$)	V _{DS} = 20V, V _{DS} = 20V,Tc = 125°C			1 10	μΑ μΑ
I _{GSS}	Gate body leakage current(V _{DS} = 0)	$V_{GS} = \pm 20V$			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1			V
R _{DS(on)}	Static drain-source on resistance	V_{GS} = 10V, I _D = 35A V_{GS} = 5V, I _D = 35A V_{GS} = 10V, I _D = 35A @Tj=125°C V_{GS} = 5V, I _D = 35A @Tj=125°C		0.0059 0.007 0.0091 0.0108	0.0073 0.013 0.0113 0.0201	Ω Ω Ω

Table 3. On/off states

Table 4. Dynamic

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Symbol	Parameter	Test condictions	Min.	Тур.	Max.	Unit
g _{fs} ⁽¹⁾	Forward transconductance	V _{DS} =10V, I _D = 15A		40		S
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} =25V, f=1MHz, V _{GS} =0		2200 380 49		pF pF pF
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V_{DD} =15V, I_D = 70A V_{GS} =5V (see Figure 7)		15.7 8.3 3.4	21	nC nC nC
Q _{gls} ⁽²⁾	Third-quadrant gate charge	V _{DS} <0V, V _{GS} =10V		15		nC
R _G	Gate input resistance	f=1MHz Gate DC Bias =0 Test signal level =20mV open drain		1.5		Ω

1. Pulsed: pulse duration = $300\mu s$, duty cycle 1.5%

2. Gate charge for synchronous operation: see Appendix A: Power losses estimation

			-		-	-
Symbol	Parameter	Test condictions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r t _{d(off)} t _f	Turn-on delay time Rise time Turn-off delay time Fall time	V_{DD} =15V, I _D =35A, R _G =4.7 Ω , V _{GS} =5V (see Figure 13)		21 95 19 15		ns ns ns ns

Table 5. Switching times

Table 6.Source drain diode

Symbol	Parameter	Test condictions	Min	Тур.	Max	Unit
I _{SD}	Source-drain current				70	А
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)				280	А
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} =35A, V _{GS} =0			1.3	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} = 70A, di/dt=100A/μs, V _{DD} =20V, Tj=150°C (<i>see Figure 18</i>)		32 51 3.2		ns nC A

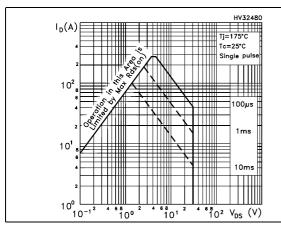
1. Pulse width limited by safe operating area

2. Pulsed: pulse duration = $300\mu s$, duty cycle 1.5%

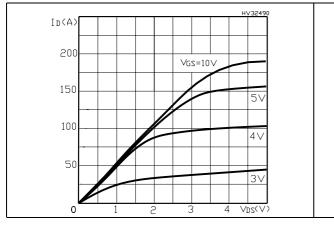


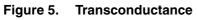
2.1 Electrical characteristics (curves)

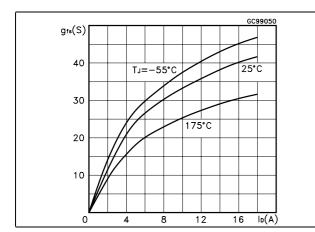
Figure 1. Safe operating area

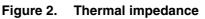












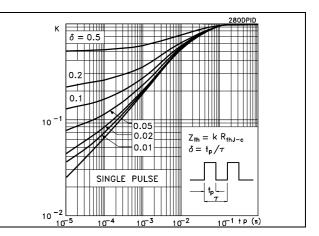


Figure 4. Transfer characteristics

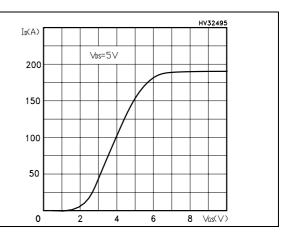


Figure 6. Static drain-source on resistance

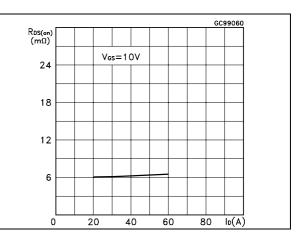


Figure 7. Gate charge vs gate-source voltage Figure 8. Capacitance variations

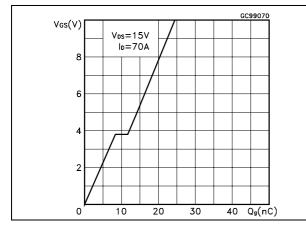


Figure 9. Normalized gate threshold voltage vs temperature

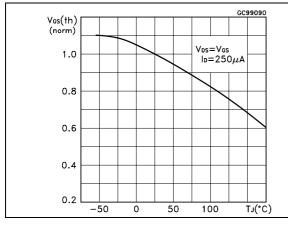


Figure 11. Source-drain diode forward characteristics

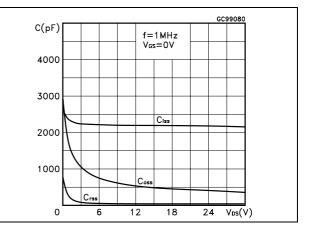


Figure 10. Normalized on resistance vs temperature

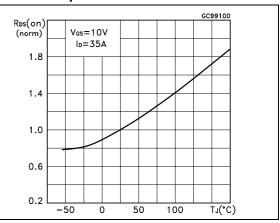
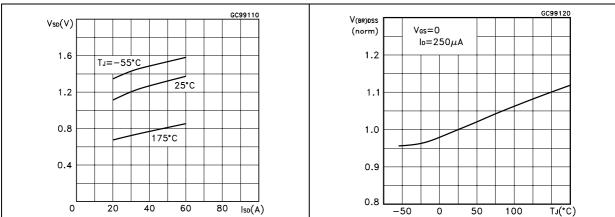


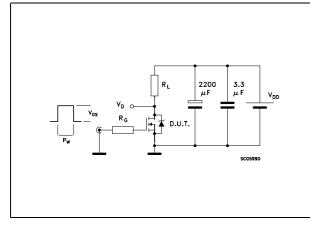
Figure 12. Normalized B_{VDSS} vs temperature

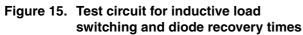


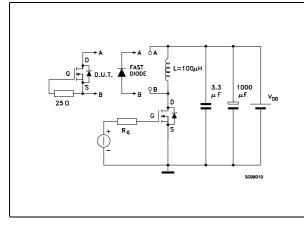
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3 Test circuit

Figure 13. Switching times test circuit for resistive load



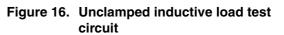






V DD ‡7K Ω 1ΚΩ 📥 100nF I_G=CONST V₁=20V=V_{GMAX} 100 Ω D.U.T. ¥ \cap _____2200 _____μF 2.7KΩ ۷G -47κ Ω <u>1KΩ</u> SC06000

Figure 14. Gate charge test circuit



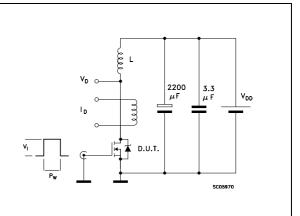
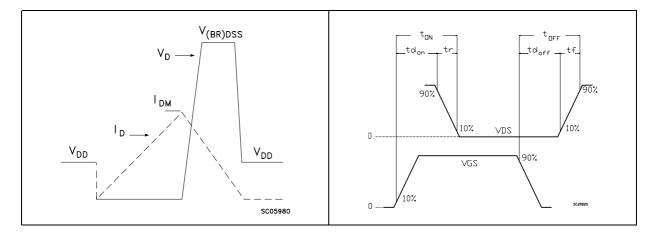
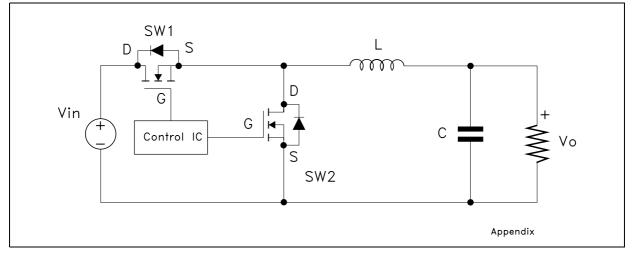


Figure 18. Switching time waveform



Appendix A Power losses estimation

Figure 19. Buck converter



The power losses associated with the FETs in a synchronous buck converter can be estimated using the equations shown in the table below. The formulas give a good approximation, for the sake of performance comparison, of how different pairs of devices affect the converter efficiency. However a very important parameter, the wotking temperature, is not considered. The real device behavior is really dependent on how the heat generated inside the devices is removed to allow for a safer working junction temperature.

The low side (SW2) device requires:

- Very low R_{DS(on)} to reduce conduction losses
- Small Q_{als} to reduce the gate charge losses
- Small Coss to reduce losses due to output capacitance
- Small Q_{rr} to reduce losses on SW₁ during its turn-on
- The C_{gd}/C_{gs} ratio lower than V_{th}/V_{gg} ratio especially with low drain to source voltage to avoid the cross conduction phenomenon.

The high side (SW1) device requires:

- Small Rg and Lg to allow higher gate current peak and to limit the voltage feedback on the gate
- Small Q_g to have a faster commutation and to reduce gate charge losses
- Low R_{DS(on)} to reduce the conduction losses



		High side switch (SW1)	Low side switch (SW2)	
Pconduction		$R_{DS(on)} \bullet I_L^2 \bullet \delta$	$R_{DS(on)} \bullet I_{L}^{2} \bullet (1 - \delta)$	
Pswitching		$V_{in} \bullet (Q_{gsth(SW1)} + Q_{gd(SW1)}) \bullet f \bullet \frac{I_L}{I_g}$	Zero voltage switching	
P _{diode}	Recovery	Not applicable	¹ V _{in} ● Q _{rr(SW2)} ● f	
uiode	Conduction	Not applicable	V _{f(SW2)} • I _L • t _{deadtime} • f	
P _{gate(Qg)}		$Q_{g(SW1)} \bullet V_{gg} \bullet f$	Q _{gls(SW2)} ● V _{gg} ● f	
P _{Qoss}		$\frac{V_{in} \bullet Q_{oss(SW1)} \bullet f}{2}$	$\frac{V_{in} \bullet Q_{oss(SW2)} \bullet f}{2}$	

Parameter	Meaning
d	Duty-cycle
Q _{gsth}	Post threshold gate charge
Q _{gls}	Third quadrant gate charge
Pconduction	On state losses
Pswitching	On-off transition losses
Pdiode	Conduction and reverse recovery diode losses
Pgate	Gate driver losses
P _{Qoss}	Output capacitance losses

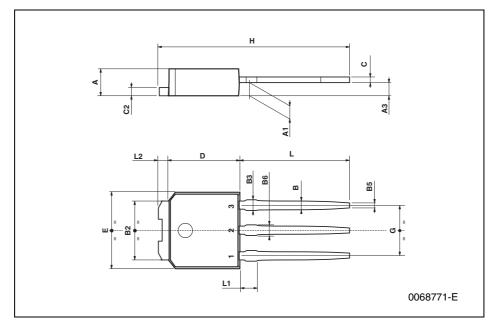
4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com



DIM.	mm			inch			
Dim.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
А	2.2		2.4	0.086		0.094	
A1	0.9		1.1	0.035		0.043	
A3	0.7		1.3	0.027		0.051	
В	0.64		0.9	0.025		0.031	
B2	5.2		5.4	0.204		0.212	
B3			0.85			0.033	
B5		0.3			0.012		
B6			0.95			0.037	
С	0.45		0.6	0.017		0.023	
C2	0.48		0.6	0.019		0.023	
D	6		6.2	0.236		0.244	
E	6.4		6.6	0.252		0.260	
G	4.4		4.6	0.173		0.181	
Н	15.9		16.3	0.626		0.641	
L	9		9.4	0.354		0.370	
L1	0.8		1.2	0.031		0.047	
L2		0.8	1		0.031	0.039	

TO-251 (IPAK) MECHANICAL DATA



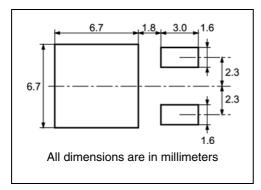
DIM.		mm.			inch		
UIIVI.	MIN.	ТҮР	MAX.	MIN.	TYP.	MAX	
А	2.2		2.4	0.086		0.094	
A1	0.9		1.1	0.035		0.043	
A2	0.03		0.23	0.001		0.009	
В	0.64		0.9	0.025		0.03	
b4	5.2		5.4	0.204		0.212	
С	0.45		0.6	0.017		0.023	
C2	0.48		0.6	0.019		0.023	
D	6		6.2	0.236		0.244	
D1		5.1			0.200		
Е	6.4		6.6	0.252		0.260	
E1		4.7			0.185		
е		2.28			0.090		
e1	4.4		4.6	0.173		0.18	
Н	9.35		10.1	0.368		0.397	
L	1			0.039			
(L1)		2.8			0.110		
L2		0.8			0.031		
L4	0.6		1	0.023		0.03	
R		0.2			0.008		
V2	0°		8°	0°		8°	
			<u>c2</u>		PAD		
	H H						

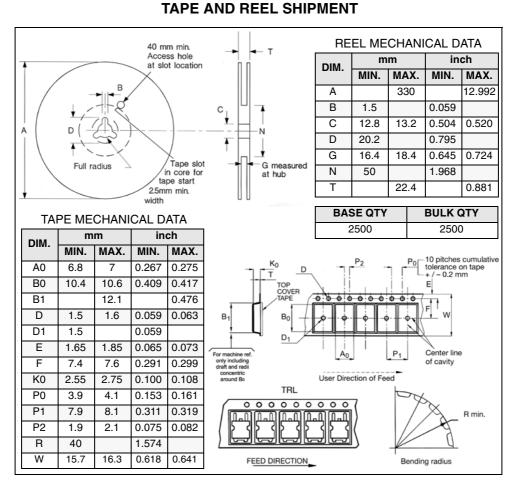


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5 Packaging mechanical data

DPAK FOOTPRINT





6 Revision history

Date	Revision	Changes
29-Jun-2006	1	First Release



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